

Substitute for form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/603,019
				Filing Date	June 26, 2003
				First Named Inventor	Shunpei YAMAZAKI et al.
				Art Unit	2818
				Examiner Name	Dung-Anh LE
Sheet	1	of	2	Attorney Docket Number	740756-2626

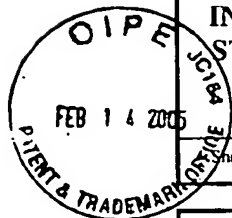
U.S. PATENT DOCUMENTS					
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
Dh		US-5,323,042 ✓	06-21-1994	MATSUMOTO	11
		US-5,412,493 ✓	05-02-1995	KUNII et al.	11
		US-5,528,056 ✓	06-18-1996	SHIMADA et al.	11
		US-5,594,569 ✓	01-14-1997	KONUMA et al.	11
		US-5,652,158 ✓	07-29-1997	BAE	11
		US-5,757,444 ✓	05-26-1998	TAKEMURA	11
		US-5,767,930 ✓	06-16-1998	KOBAYASHI et al.	11
		US-5,852,488 ✓	12-22-1998	TAKEMURA	11
		US-5,953,582 ✓	09-14-1999	YUDASAKA et al.	11
		US-6,013,929 ✓	01-11-2000	OHTANI	11
		US-6,088,070 ✓	07-11-2000	OHTANI et al.	11
		US-6,140,162 ✓	10-31-2000	YEO	11
		US-6,166,436 ✓	12-26-2000	MAEDA et al.	11
		US-2001/0000627 A1 ✓	05-03-2001	HAYAKAWA et al.	11
		US-6,323,490 B1 ✓	11-27-2001	IKEDA et al.	11
		US-6,337,731 B1 ✓	01-08-2002	TAKEMURA	11
		US-6,399,988 B1 ✓	06-04-2002	YAMAZAKI	11
		US-6,531,713 B1 ✓	03-11-2003	YAMAZAKI	11
		US-6,579,736 B2 ✓	06-17-2003	YAMAZAKI	11
		US-6,693,681 B1 ✓	02-17-2004	TAKEMURA	11
Dh		US-6,734,924 B2 ✓	05-11-2004	HIRAKATA et al.	11
		US-6,777,255 B2 ✓	08-17-2004	YAMAZAKI	11

FOREIGN PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
Dh		JP 63-222443 ✓	09-16-1988	OKABE	11	Abst
		JP 03-091721	04-17-1991	SAITO et al.	11	Abst
		JP 05-307165	11-19-1993	OZAWA	11	Abst
		JP 07-326767	12-12-1995	IKEDA	11	Abst
		JP 09-074204	03-18-1997	MOROSAWA	11	Abst
		JP 10-012895	01-16-1998	KAWAURA et al.	11	Abst
Dh		JP 11-097701	04-09-1999	INOUE	11	Abst
		EP 0 989 614 A2	03-29-2000	YAMAZAKI et al.	11	

Examiner Signature	Date Considered
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¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at 222.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.



Substitute for form 1449B/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Complete if Known

Application Number	10/603,019
Filing Date	June 26, 2003
First Named Inventor	Shunpei YAMAZAKI et al.
Group Art Unit	2818
Examiner Name	Dung-Anh LE
Attorney Docket Number	740756-2626

Sheet	2	of	2
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials [*]	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
De		U.S. Application No. 09/542,473; Filed: April 4, 2000; Takayuki IKEDA et al.; ELECTROOPTICAL DEVICE AND A METHOD OF MANUFACTURING THE SAME	
		H. FURUE et al., P-78: Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLC D Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability; SID 98 Digest, pgs. 782-785.	
		T. YOSHIDA et al., 33.2: A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time, SID 97 Digest, pgs. 841-844.	
De		M. LEE et al., New Polycrystalline Silicon TFT's with Selectively Doped Region in The Channel, IDW '99 Proceedings of The Sixth International Display Workshops, December 1-3, 1999, pgs. 1097-1098.	

Examiner Signature	De	Date Considered	3/2005
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete if known

Application Number	10/603,019
Filing Date	June 26, 2003
First Named Inventor	Shunpei YAMAZAKI et al.
Art Unit	2818
Examiner Name	LE, Dung-Anh
Attorney Docket Number	740756-2626

U.S. PATENT DOCUMENTS

Cite No. ¹	U.S. Patent Document		Publication Date MM-DD-YYYY	Name of Patent or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Paragraphs or Relevant Figures Appear
	Number - Kind Code ² (if known)				
	US-4,984,033		01-08-1991	ISHIZU et al.	
	US-5,341,012		08-23-1994	MISAWA et al.	
	US-5,818,552		10-06-1998	SATO	
	US-5,998,838		12-07-1999	TANABE et al.	
	US-6,066,860		05-23-2000	KATAYAMA et al.	
	US-6,278,131 B1		08-21-2001	YAMAZAKI et al.	
	US-2001/0029070 A1		10-11-2001	YAMAZAKI et al.	
	US-6,316,787 B1		11-13-2001	OHTANI	
	US-6,330,044 B1		12-11-2001	MURADE	
	US-6,590,229 B1		07-08-2003	YAMAZAKI et al.	
	US-6,639,244 B1		10-28-2003	YAMAZAKI et al.	
	US-2004/0056296 A1		03-25-2004	ARAO et al.	
	US-2004/0065882 A1		04-08-2004	YAMAZAKI et al.	
	US-				
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FOREIGN PATENT DOCUMENTS

Examiner Initials ³	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patent or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Paragraphs or Relevant Figures Appear	1 ⁴
		Country Code ⁵ Number ⁶	Kind Code ² (if known)				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials ³	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	1 ⁴

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Substitute for Form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	New Divisional Application
		Filing Date	June 26, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
		Art Unit	2815
		Examiner Name	G. Eckert, II
Sheet 1 of 2	Attorney Docket Number	740756-2626	

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code (if known)			
JL		US-5,182,620	01/1993	Shimada et al.	}
		US-5,739,549	04/1998	Takemura et al.	
		US-5,942,310	08/1999	Moon	
		US-6,067,132	05/2000	Kim	
		US-6,137,551	10/2000	Jeong	
		US-6,271,818	08/2001	Yamazaki et al.	
		US-6,490,014	12/2002	Ohiani et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code	Number			
JL		GB	2-307,326	05/1997	Shin et al.	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS); title of the article (when appropriate); title of the item (book, magazine, journal, serial, symposium, catalog, etc.); date, page(s), volume/issue number(s), publisher, city and/or country where published.	T ¹
JL		Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758.	

Examiner Signature	<i>JL</i>	Date Considered	4/2004
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Form PTO-1449 (Rev. 8-83)	U.S. Department of Commerce Patent and Trademark Office	Attorney Docket: 740756-2626	Serial No.
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			
		Applicant: Shunpei YAMAZAKI et al.	
		Filing Date: June 26, 2003	Group: 2815

U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
<i>De</i>	5,643,826	07/01/1997	Ohtani et al.			
	5,923,962	07/13/1999	Ohtani et al.			
	5,895,933	04/20/1999	Zhang et al.			
	5,882,960	03/16/1999	Zhang et al.			
	5,608,251	03/04/1997	Konuma et al.			
	5,620,905	04/15/1997	Konuma et al.			
	5,712,495	01/27/1998	Suzawa			
	5,856,689	01/05/1999	Suzawa			
	5,998,841	12/07/1999	Suzawa			
	4,409,724	10/18/1983	Tasch et al.			
	4,823,180	04/18/1989	Wieder et al.			
	4,851,370	07/25/1989	Doklan et al.			
	4,886,962	12/12/1989	Gofuku et al.			
	5,292,675	03/08/1994	Codama			
	5,343,066	08/30/1994	Okamoto et al.			
<i>De</i>	5,365,079	11/15/1994	Kodaira et al.			
	5,616,935	04/01/1997	Koyama et al.			
	5,508,209	04/16/1996	Zhang et al.			

FOREIGN PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation
<i>De</i>	07-130652	05/19/1995	Japan			Abstract
	07-321339	12/08/1995	Japan			Abstract
	09-312260	12/02/1997	Japan			Abstract
	10-056184	02/24/1998	Japan			Abstract
	10-247735	09/14/1998	Japan			Abstract
	07-130974	05/19/1995	Japan			Abstract
	07-135323	05/23/1995	Japan			Abstract
	07-169974	07/04/1995	Japan			Abstract
	07-169975	07/04/1995	Japan			Abstract
	07-218932	08/18/1995	Japan			Abstract
<i>De</i>						
Examiner <i>De</i>			Date Considered <i>2/2004</i>			

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